

Search Notes



Application No.	Applicant(s)
10/604,244	TAI ET AL.
Examiner	Art Unit
Toan M Le	2863

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Wafer In-line Yield Prediction	9/1/2004	TL
Wafer Yield Analysis; Statistical; Regression; Sample	9/1/2004	TL
Wafer Quality Control Analysis; Parameter; Lot; Sample	8/31/2004	TL
Quality Control, Sample, Parameter, Search, Database, Analyzing, Correlating, Wafer	8/31/2004	TL